Se	arch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/601,441	SUEN ET AL.	
Examiner	Art Unit	
Eric Chang	2116	

	SEARCHED		
Class	Subclass	Date	Examiner
713	401	10/30/2006	EC
			-

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST USPAT/PGPUB EPO/JPO	10/30/2006	EC